

THE MIXED ANALOG/DIGITAL SHAPER OF THE LHCb PRESHOWER

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Abstract

The LHCb preshower signals show so many fluctuations at low energy that a classical shaping is not usable at all. Thanks to the fact that the fraction of the collected energy during a whole LHC beam crossing time is 85%, we studied the special solution we presented at Snowmass 1999 workshop. This solution consists of 2 interleaved fast integrators, one being in integrate mode when the other is digitally reset. Two track-and-hold and an analog multiplexer are used to give at the output 85% of the signal plus 15% of the previous one. These 15% are digitally computed from the previous sample, and subtracted. A completely new design of this solution had to be made, see figure 2. This new design is described, including new methods to decrease the supply voltage and the noise, as well as to increase the quality of the reset and the linearity. An output stage, consisting of a AB class push-pull using only NPN transistors is also described. Laboratory and beam test results are given.

I. INTRODUCTION

The LHCb preshower is used for the level 0 trigger, for which a threshold corresponding to 5 minimum ionization particle (MIP) is applied, with a 5% accuracy. This detector is also used to improve electron and photon measurement up to 100 MIP. These two functions give us a dynamic range of 0.1 to 100 MIP (i.e. 10 bits).

The study of the signal [1] given by a scintillator cell and the 64 channels Hamamatsu PMT, with a good agreement with their simulation, shows us that at low energy, the dominant effect is the statistical fluctuation of the photoelectron collection, while at high energy the dominant effect is the PMT saturation which begin at 0.6 mA, see figure 1. These conditions, and the fact that the signal length is always longer than 25 ns, drive us to the solution described before. We don't change the main electronic choices we made on 1999 [2]:

- a fully differential design to minimize the noises;
- bipolar transistors at the input stages to reduce the offsets;
- CMOS transistors to save power and design integrator switches;
- AMS 0.8 μm BiCMOS technology and CADENCE tools.

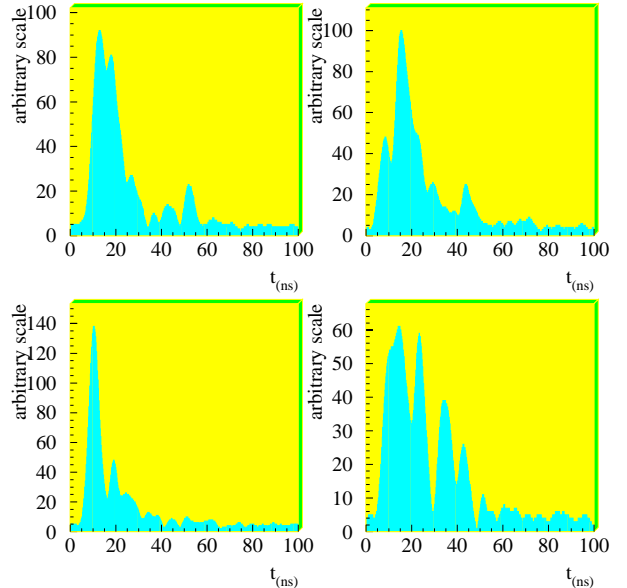


Figure 1: cosmic events

However, we had to redesign the chip due to the following considerations:

- because of the PMT saturation, we had to increase the gain by a factor 20, and then we had to take more care of the noise and offset effects. For the noise, the integrator input stage was changed, and for the offset and the operating point stability a special common mode feedback loop was added;
- we need a very high quality reset, to be able to compute the subtraction with a negligible error, even in the cases of a maximum signal immediately followed by a "trigger level" one: the integrator itself was changed;
- the supply voltage had to be decreased down to $\pm 2.75\text{ V}$ to match the foundry specifications, and to obtain the "small power consumption" of 100 mW/channel;
- to carry the 6000 output analog signals, we plan to use simple ethernet differential cables on up to 20 m long, in this case, we must adapt this cable at both end, and then have to double the dynamic. To save power, this dynamic is done in the last stage by designing a differential analog multiplexer with a gain of two, and a $\pm 2\text{ V}$ dynamic range with a $\pm 2.75\text{ V}$ supply. This required the design of parallel linearity correction instead of the previous serial one;

- we have to drive efficiently the cable without extra chips: an "all NPN A-B class push-pull " was designed.

II. DESIGN CONSIDERATIONS

Most blocks of the chip are designed around a simple bipolar differential pair: this scheme is stable, easy to use and economic in term of silicon area. In addition, in a fully differential design, each signal has its opposite, which is very useful to compensate parasitic effects. In our case, we have to take care of the linearity: our calibration will be done essentially by the MIP values which are only 10 ADC counts. For this reason we need a non linearity smaller than 1%, and we have five blocks (i.e. five non linearity sources) in serial, see figure 2.

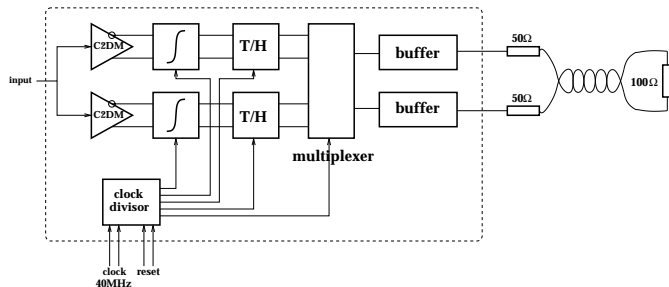


Figure 2: one channel design

It is well known that the non linearity of differential pair, essentially due to the variation of the base-emitter voltage of the two transistors is easily corrected by the addition of one diode (gain of 1), or two diodes (gain of 2) in the collector branches to obtain the same voltage drop in emitter and collector load, see figure 3. However, the consequence of this "serial correction" is the lost of one or two diode voltage drops which is incompatible with a large dynamic range using small voltage power supply. The idea we explore to overcome this problem is to replace this "serial correction" by a parallel one, see figure 4.

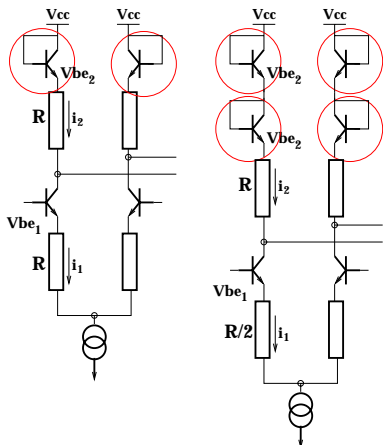


Figure 3: serial compensation

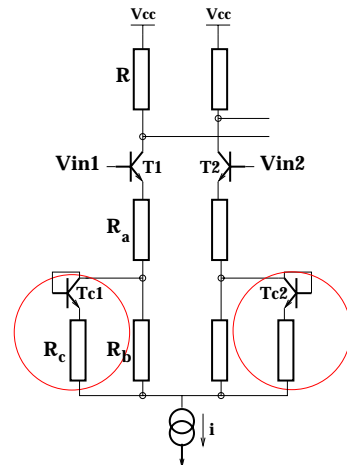


Figure 4: parallel compensation

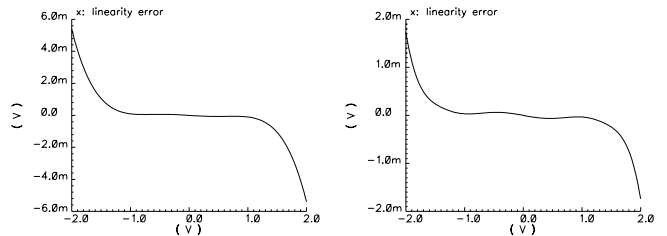


Figure 5: without

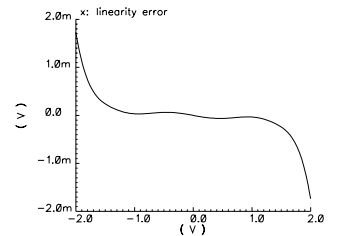


Figure 6: under

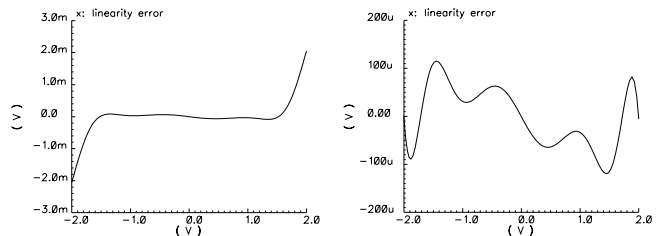


Figure 7: over

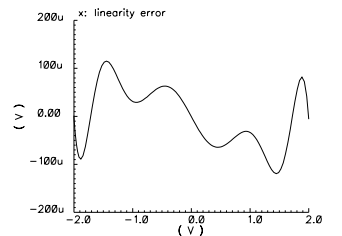


Figure 8: right

In this new correction, the lost of gain is compensated by decreasing the emitter load in the opposite branch. The gain obtained is double: we obtain a very good correction without loss of dynamic range and the over-compensation is possible. This is useful to compensate two stages with only one parallel correction.

As an example, see figure 3 and 4, on this application, a gain of 2 is needed in the multiplexer stage: using this correction a non linearity error of only $\pm 100 \mu V$ was obtained for a 4 volt ($\pm 2 V$) dynamic range including output stage, using a $\pm 2.75 V$ power supply. Figures 5, 6, 7 and 8 shown the error obtained in this example in the cases of no compensation (5), under-compensation (6), over-compensation (7) and right compensation (8).

The solution described here is very sensitive to the clock jitter which determines the integration precision. For this reason, we decide to send to the chip the main 40 MHz clock, and to make the 20 MHz clock inside the chip. In the other hand to protect the analog parts of the chip

against clock cross talk, the clock connections in the chip are all bipolar, low level, ECL, and the CMOS clocks of the integrators are generated inside each integrator block.

III. BUILDING BLOCKS

1.- COMMON TO DIFFERENTIAL MODE BLOCK (C2DM)

The final scheme chosen is a voltage input current output block, instead of the voltage amplifier of the first version, see figure 9. The C2DM outputs can be considered as grounded (virtual ground of the integrator): $i_1 = -i_2 = V_{in}/2R_0$.

The value of the current I determines only the speed, as the values of r and V only the operating output point, provided that the value of r remains high with respect to the integrator input impedance. These values are optimized for the noise, the power supply is reduced by 3 diodes and darlington transistors are used to reduce input current and allow to set the output operating point near the ground.

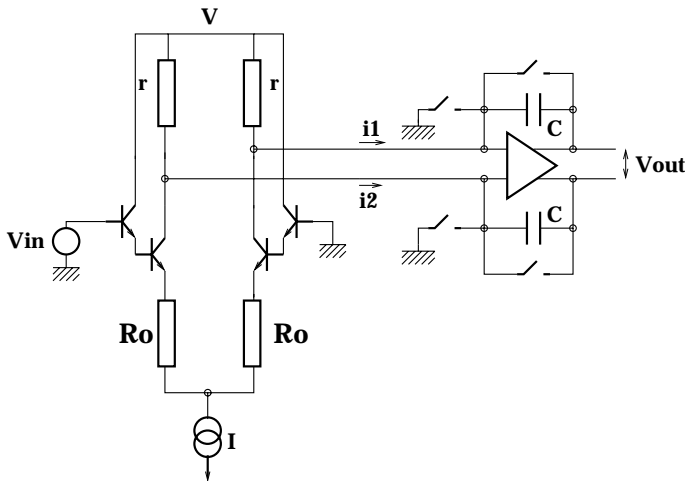


Figure 9: C2DM and integrator

2.- SWITCHED INTEGRATOR

This block, see figure 9, is built around the wide band high gain amplifier. It has two gain stages, the first is optimized to minimize the offset, the second is a rail to rail CMOS output. The connection between the two stages is a simple follower for the PMOS's and a fixed voltage drop (diodes and resistor at constant current) for the NMOS's.

Two originalities are implemented :

During the integrate phase, from the DC point of view, the integrator is an open loop high gain amplifier: as a consequence the offset and the operating point stability are critical: for the offset greatest care was taken on the input stage (resistor load and transistors doubled and designed as a cross), and an extra feedback loop, acting only on the common mode signal was added see figure 10: first the common mode voltage is obtained by summation of the two complementary outputs with 2 resistors. This voltage is then compared to ground and the error result amplified

and applied with the same polarity on the two inputs. As a result, the output common voltage is maintained to ground, and the offset is reduced.

During the reset phase, inputs and outputs are shorted. As a consequence the gain becomes very low and the virtual ground is not achieved. To overcome this problem two extra switches are added at the inputs. The four switches are designed with complementary MOS as usual to minimise the injected charge effect.

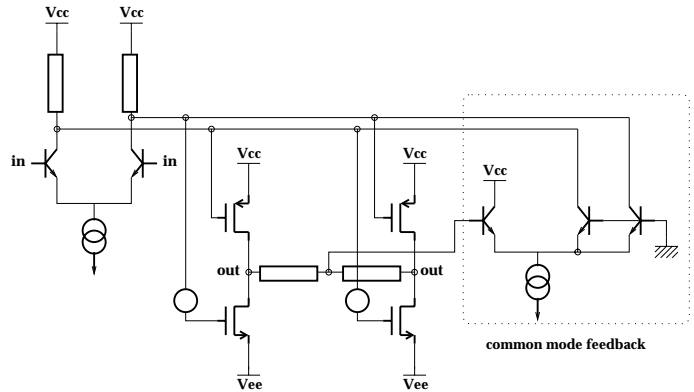


Figure 10: AOP with C.M. feedback

Results: the simulation results show a gain of 5 000 and a very high quality reset. The simulated linearity is perfect. An integrator was realized and tested alone. The test results are in very good agreement with the simulation: the offsets measured at the output vary from a few mV to a maximum of 100mV and the linearity is better than our measurement capability.

3.- TRACK AND HOLD

The used structure is described by Pieter Vorenkamp [3] and Jean-Marie Bussat [4], and already used and described several times. The compensation of the base emitter parasitic capacity was unchanged, but the "serial" linearity compensation was replaced by our new parallel one to be more comfortable on dynamic and also to obtain the output operating point as high as possible. Under these condition, the $\pm 1 V$ dynamic range was easily obtained with a linearity of few per thousand. These results were confirmed by the tests of the prototypes, see the LHCb web site [5].

4.- DIFFERENTIAL ANALOG MULTIPLEXER

The circuit was interesting to design: in this final version it is the key block where we had to go from $\pm 1 V$ to $\pm 2 V$ dynamic range, in a 25 ns multiplexing operation without any crosstalk from one input to the other.

We start from the simple switch of two identical differential pairs of the figure 11. This scheme shows the following imperfections :

- it is a little too slow, specially to return to zero when the other input is high: The correction found is a simple pull up resistor, see figure 12 ;
- the non linearity errors, as explain before, was cor-

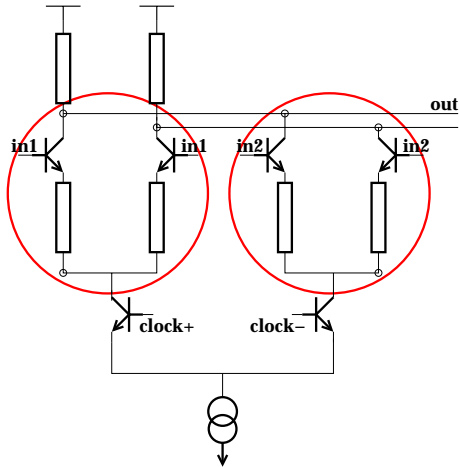


Figure 11: multiplexer design

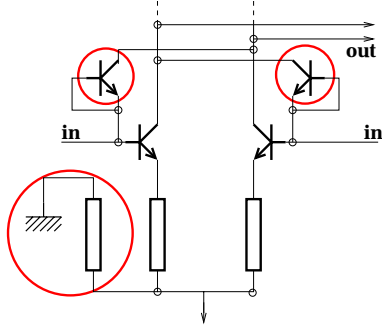


Figure 12: multiplexer detail

rected with the "parallel compensation" ;

- as on many other multiplexers, there is a little cross talk between the two inputs, specially when the unused input is fast and high. Here this fact is due to the fact that the blocked transistors of the non used input act as parasitic capacitor and inject on the output a little part of their own signal. Thanks to the fact that this design is fully differential, we used two extra transistors, always blocked, to inject also the opposite parasites, see figure 12. Notice that the 4 transistors have exactly the same base and collector operating points. As a result, the compensation is perfect, and the cross talk disappears fully.

5.- OUTPUT BUFFER

The output buffer is also a challenge: the consumption of the very front end board is very critical as we have to handle 64 channels and drive them on 20 meter cables, on a 7×7 cm PC board including the 64 channel phototube! A true class B or AB push-pull using only NPN transistors was designed. It can be seen on the figure 13 that transistors $T1$ acts as a usual complementary push pull. The transistor $T2$, which replaces the classical PNP is driven by a control loop for which the transistors $T3$, $T4$ and $T5$ are added. $T1 + T3$ and $T4 + T5$ form a current mirror: they have same base and same emitter voltage. A fraction of the output current, determined by the size

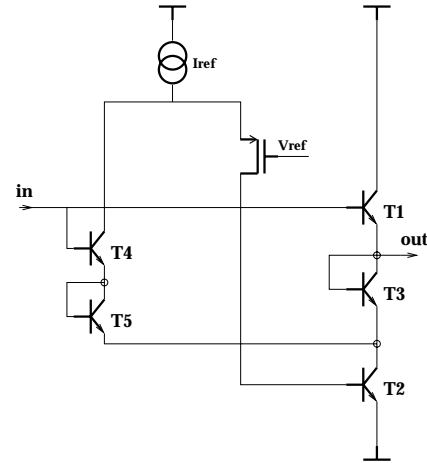


Figure 13: buffer design

ratio of $T1$, $T3$ and $T4$, $T5$, is "measured" by $T4 + T5$ and subtracted to I_{ref} . The part of I_{ref} which is not taken by $T4$, $T5$ is apply to the base of $T2$ by the PMOS transistor.

It is easy to verify that this feedback is stable: if a positive signal occurs, the current of $T1$ increases, its V_{be} increases and then the V_{be} of $T4$ and $T5$ increase. As a consequence, more current is taken to I_{ref} by $T4$ and $T5$ and the current given to $T2$ by the PMOS decreases to allow the output voltage to increase. The same analyze is easy to do with a negative going signal. The simulation confirms that this circuit is a true push pull. It is interesting to notice that the current feedback parameters are not critical at all, and very easy to adjust. It is also interesting to notice that the maximum dynamic range we can reach is only limited by the power supply and the lost of two V_{be} ($T1$ and $T3$), exactly like in a complementary Push Pull. The following table shows the results which could be easily reached with this output stage for 3 different quiescent currents:

power supply	quiescent currents	linearity error on 2 volts	rise time
± 2.75 V	25 mA	2 mV max	2 ns
± 2.75 V	16 mA	5 mV max	3.5 ns
± 2.75 V	12 mA	8 mV max	5 ns

For our application, we chose to operate at 16mA. Notice that, as explain before, the 5 mV non linearity error was corrected in the parallel compensation of the previous stage to reach, in simulation $\pm 100 \mu V$ error with the two stages together.

IV. MEASUREMENTS

As usual, each block was individually realized and tested, then a complete one channel prototype was realized and tested, both in laboratory and in test beam. Finally, after one iteration, a 4 channel and then the final 8 channels chips were produced. The results were in very good agreement with the simulation, some details can be found on the LHCb web site [5].

The functionalities of the chip were carefully verify, laboratory and test beam test and measurement were done, their results are summarized bellow.

1.- LABORATORY TESTS

Offset: as expected offset dispersion is lower than 100 mV.

Gains: the gain dispersion (few per cent) is negligible behind the channel gain dispersion of the phototube.

Switching and rise time: the results of the "multiplexer-buffer alone" test show their total agreement with simulation, without any overshoot, and with the predicted rise time.

Global laboratory tests are summarized in figures 14 and 15 which show the simulated output just near the measured one, and quantified by a global measure of the linearity, which is the most important test. As we didn't have any very precise pulse generator in term both of time jitter and amplitude, we test the chip on its worst operating mode; i.e. with a very large input pulse given by a the AWG2022 Tektronix 12 bits arbitrary wave form generator. The output of the chip is then transmitted to the same ADC driver as used on the front end board and to the 14 bits 65 MS/s ADC AD6644. The result which represents the sum of errors of the generator, the chip, the opamp and the ADC is shown figure 14. This measured error is less than one LSB for the low signals and less than one per cent along the whole dynamic range. As this error is in the same order of magnitude of these of our test bench, the fact that they are not exactly so good than the simulated ones is not significant. In any case, they fit with the requirements of the experiment.

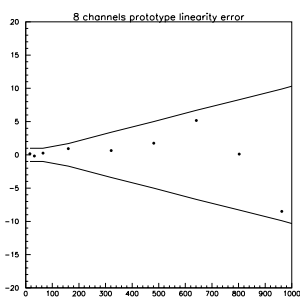


Figure 14: linearity

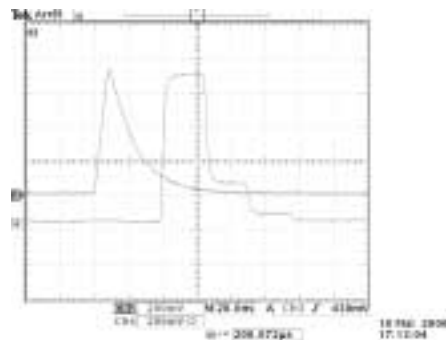


Figure 15: chip in/out

The noise was measured: we obtain the value of $650 \mu V$ which fits our requirement, as it is less than one LSB.

2.- TEST BEAM RESULTS

During the last LHCb test beam (september 2001), we test for the first time the final version. The figure 17 shows the output of the chip after a 15 meter cable for one MIP. The noise value, see figure 16, was obtained by histogramming the chip output few periods before the trigger. The value of $700 \mu V$ we obtain shows that, in the poor conditions of this test, the performances of the chip was not degraded.

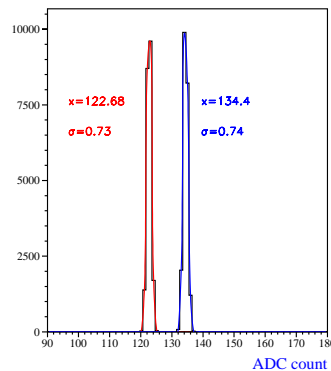


Figure 16: noise

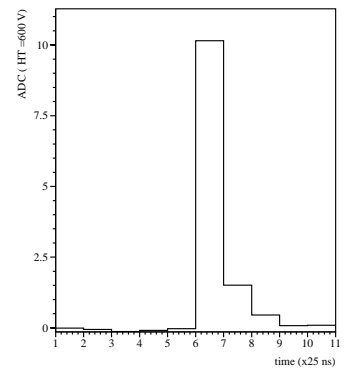


Figure 17: the MIP

V. CONCLUSION

The mixed analog/digital shaper of the LHCb preshower, based on switched integrator, track and hold, multiplexer and cable push pull driver was successfully designed, realized and tested. The results, in very good agreement with simulations give:

- a dynamic range higher than $\pm 2V$ with $\pm 2.75V$ power supply;
- a linearity better than 1% or 1 mV over the whole dynamic range;
- a noise smaller than $650 \mu V$;
- a consumption of 100 mW per Channel;
- a silicon area of $1.5 mm^2$ per channel, 8 channels per chip.

Thanks to the full differential design, all the corrections were easily done, and the output noise was not affected at all by the 40 MHz clock.

References

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